



8XC51SL/LOW VOLTAGE 8XC51SL KEYBOARD CONTROLLER

80C51SL — CPU with RAM and I/O; $V_{CC} = 5V \pm 10\%$

81C51SL — 16K ROM Preprogrammed with SystemSoft Keyboard Controller and Scanner Firmware. $V_{CC} = 5V \pm 10\%$.

83C51SL — 16K Factory Programmed ROM. $V_{CC} = 5V \pm 10\%$.

87C51SL — 16K OTP ROM. $V_{CC} = 5V \pm 10\%$.

Low Voltage 80C51SL— CPU with RAM and I/O; $V_{CC} = 3.3V \pm 0.3V$

Low Voltage 81C51SL— 16K ROM Preprogrammed with SystemSoft Keyboard Controller and Scanner Firmware. $V_{CC} = 3.3V \pm 0.3V$.

Low Voltage 83C51SL— 16K Factory Programmed ROM. $V_{CC} = 3.3V \pm 0.3V$.

Low Voltage 87C51SL— 16K OTP ROM. $V_{CC} = 3.3V \pm 0.3V$.

- Proliferation of 8051 Architecture
- Complete 8042 Keyboard Control Functionality
- 8042 Style Host Interface
- Optional Hardware Speedup of GATEA20 and RCL
- Local 16 x 8 Keyboard Switch Matrix Support
- Two Industry Standard Serial Keyboard Interfaces; Supported via Four High Drive Outputs
- 5 LED Drivers
- Low Power CHMOS Technology
- 4-Channel, 8-Bit A/D
- Interface for up to 32 Kbytes of External Memory
- Slew Rate Controlled I/O Buffers Used to Minimize Noise
- 256 Bytes Data RAM
- Three Multifunction I/O Ports
- 10 Interrupt Sources with 6 User-Definable External Interrupts
- 2 MHz–16 MHz Clock Frequency
- 100-Pin PQFP (8XC51SL)
100-Pin SQFP (Low Voltage 8XC51SL)

The 8XC51SL, based on Intel's industry-standard MCS[®] 51 microcontroller family, is designed for keyboard control in laptop and notebook PCs. The highly integrated keyboard controller incorporates an 8042-style UPI host interface with expanded memory, keyboard scan, and power management. The 8XC51SL supports both serial and scanned keyboard interfaces and is available in pre-programmed versions to reduce time to market. The Low Voltage 8XC51SL is the 3.3V version optimized for even further power savings. Throughout the remainder of this document, both devices will generally be referred to as 51SL.

The 8XC51SL is a pin-for-pin compatible replacement for the 8XC51SL-BG. It does, however have some additional functionality. Those additional functions are as follows:

1. 16K OTP ROM: The 8XC51SL-BG had only 8K of ROM.
2. New Register Set: The 8XC51SL adds a second set of host interface registers available for use in supporting power management. This required an additional address line (A1) for decoding. To accommodate this, one V_{CC} pin was removed. However, in order to maintain compatibility with the -BG version, an enable bit for this new register set was added in configuration register 1. This allows the 8XC51SL to be drop in compatible to existing 8XC51SL-BG designs; no software modifications required.

NOTE:

The changes made to the V_{CC} pins require that all three V_{CC} pins be properly connected. Failing to do so could result in high leakage current and possible damage to the device.

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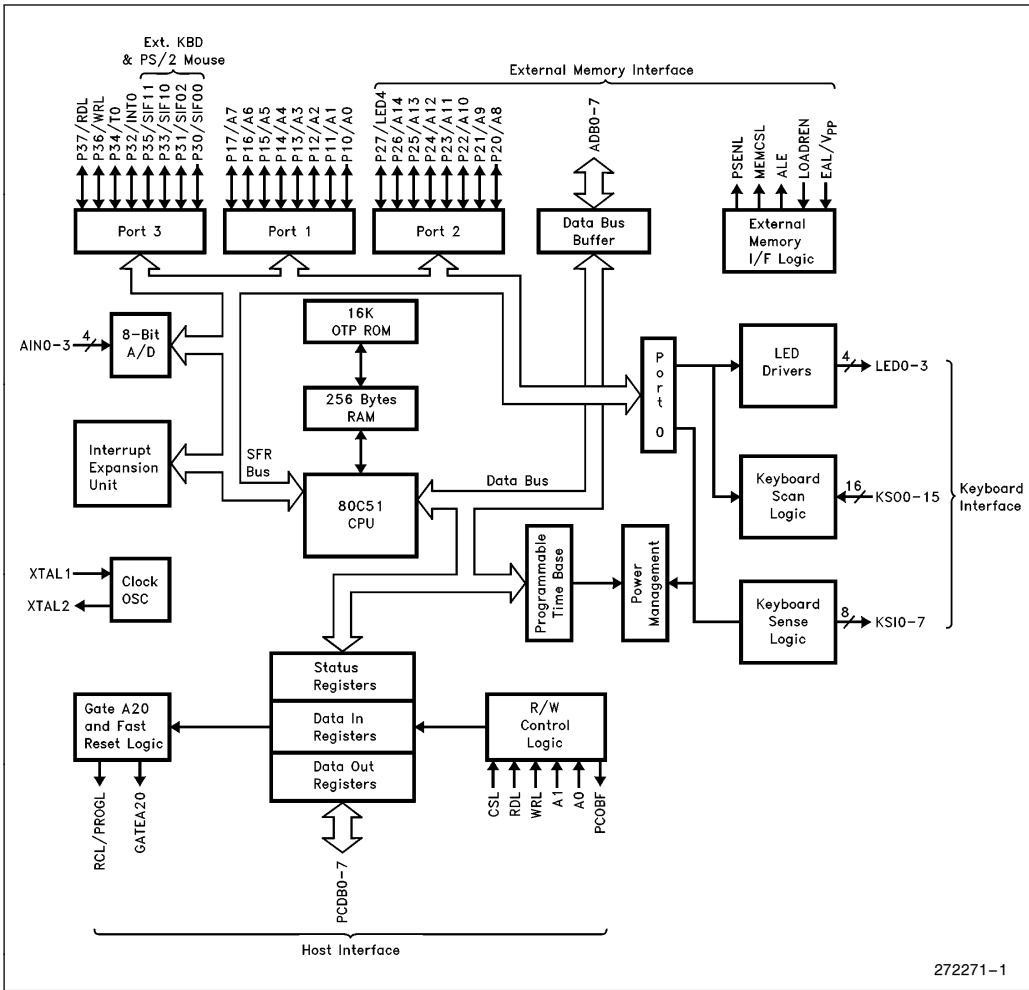


Figure 1. Block Diagram

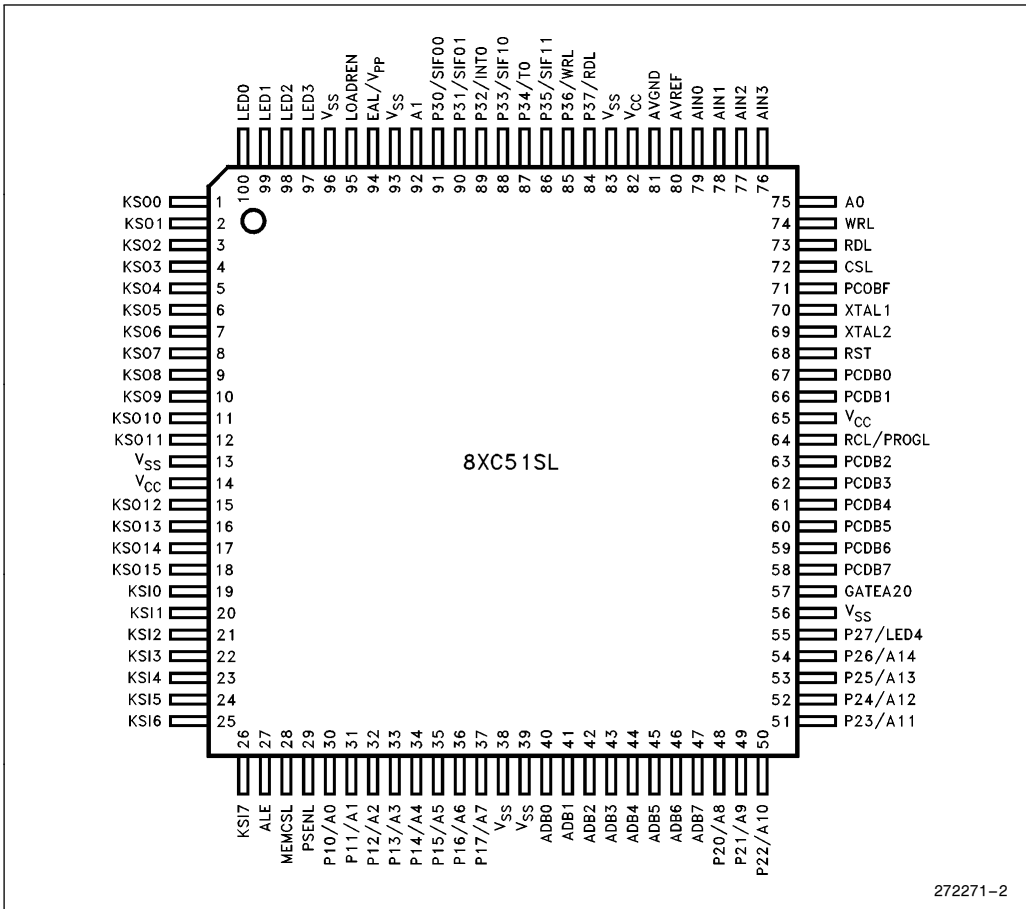


Figure 2. Connection Diagram (PQFP and SQFP)

PACKAGES

Part	Prefix	Suffix	Package Type
8XC51SL	KU	AH	100-Pin PQFP
Low Voltage 8XC51SL	SB	AL	100-Pin SQFP

PIN DESCRIPTIONS

Table 1. Pin Descriptions

Symbol	Type	Description
V _{SS}		Circuit ground potential.
V _{CC}		Supply voltage during normal, Idle, and Power-Down operation; nominally +5V \pm 10% for 8XC51SL, +3.3V \pm 0.3V for Low Voltage 8XC51SL.
PCDB0–7	I/O	Host interface data bus. An 8-bit bidirectional port for data transfers between the host processor and the keyboard controller.
WRL	I	The active-low, host-interface write signal.
RDL	I	The active-low, host-interface read signal.
CSL	I	The active-low, host-interface chip select.
A0–A1	I	Host-Interface Address select inputs.
PCOBF	O	The active-high, host-interface Output Buffer Full interrupt.
GATEA20	O	Gate A20 control signal output.
RCL/PROGL	O	Host reset—active low. This pin is also the program pulse input during EPROM programming.
LED0–3	O	LED output drivers.
KSI0–7	I	Keyboard input scan lines (input Port 0). Schmitt inputs with 5K–20K pull-up resistors.
KSO0–15	O	Keyboard output scan lines.
PORT 1 P10/A0– P17/A7	I/O	Port 1 is a general-purpose, 8-bit bidirectional port with internal pull-ups. It also supports the following user-selectable functions: P10–P16 are available for connection to dedicated keyboard inputs. A0–A7 output the low-order address byte (refer to LOADREN signal).
LOADREN	I	Low address enable. When set high, address bits A0–A7 are output on P10–P17.
PORT2 P20–6/A8–14 P27/LED4	I/O	Port 2 is a general-purpose, 8-bit bidirectional port with internal pull-ups on P20–6/A8–14. It also supports the following user-selectable functions: P20–6/A8–14 output the high-order address byte. P27/LED4 is available as a fifth LED output driver (by writing to the port bit 7).
PORT 3 P30/SIF00 P31/SIF01 P32/INT0 P33/SIF10 P34/T0 P35/SIF11 P36/WRL P37/RDL	I/O	Port 3 is a general-purpose, 8-bit bidirectional port. P32/INT0, P34/T0, P36/WRL, and P37/RDL have internal pull-ups. P30/SIF00, P31/SIF01, P33/SIF10, and P35/SIF11 are high-drive open-drain outputs. It also supports the following user-selectable functions: A high-drive, open-drain output to support an external serial keyboard interface (typically CLK); RXD (8051 UART serial input port); SIF0INTL (serial interface interrupt 0). A high-drive, open-drain output to support an external serial keyboard interface (typically DATA); TXD (8051 UART serial output port). INT0L (external interrupt 0). A high-drive, open-drain output to support an external serial keyboard interface (typically mouse CLK); SIF1INTL (external interrupt 1). AUXOBF1 (output buffer full—mouse support); T0 (Timer/Counter 0 external input). A high-drive, open-drain output to support an external serial keyboard interface (typically mouse DATA); T1 (Timer/Counter 1 external input). WRL (external data memory write strobe); inactive at addresses 7FF0–7FFFH. AUXOBF2 (output buffer full interrupt); INT2L (external interrupt); RDL (external data memory read strobe); inactive at addresses 7FF0–FFFFH.

PIN DESCRIPTIONS (Continued)

Table 1. Pin Descriptions (Continued)

Symbol	Type	Description
XTAL1	I	Input to the on-chip oscillator.
XTAL2	O	Output from the on-chip oscillator.
AVGND		Analog ground potential.
AVREF		Analog supply voltage; nominally +5V ± 10% for 8XC51SL, +3.3V ± 0.3V for Low Voltage 8XC51SL.
AIN0–3	I	A/D Analog input channels.
ADB0–7	I/O	External address/data bus. Multiplexes the low-address byte and data during external memory accesses.
EAL/V _{PP}	I	External address input. When held high, the 51SL CPU executes out of internal Program Memory unless the program counter exceeds 3FFFH. When held low, the 51SL CPU always executes out of external memory. EAL is latched on the falling edge of RST. This pin also receives the programming supply voltage (V _{PP}) during EPROM programming.
ALE	O	Address Latch Enable output pulse latches the low address byte during external memory access. ALE is output at a constant rate of 1/6 the oscillator frequency, whether or not there are accesses to external memory. One ALE pulse is skipped during the execution of a MOVX instruction. ALE is disabled during Idle mode and can also be disabled via Configuration register 1 control.
PSENL	O	Program Store Enable is the read strobe to external program memory. PSENL is qualified with RDL and A15 for use with an external Flash memory. PSENL is not active when the device executes out of internal program memory.
MEMCSL	I/O	External Memory Chip Select for code space address 4000H and above, when EAL is inactive (i.e., high). For EAL low, MEMCSL is active. Goes inactive during Idle mode and Power-Down mode. If external memory interfacing is not required, MEMCSL can be configured as a general purpose I/O (controlled via Configuration register 1).
RST	I	Resets the keyboard controller. Hold RST high for two machine cycles.

8XC51SL/LOW VOLTAGE 8XC51SL PIN CHARACTERISTICS

Table 2. Pin Characteristics

Pin No.	Pin Name	Type	Term	Reset	PD Mode
1	KSO0	O	OD	TRI	HOLD
2	KSO1	O	OD	TRI	HOLD
3	KSO2	O	OD	TRI	HOLD
4	KSO3	O	OD	TRI	HOLD
5	KSO4	O	OD	TRI	HOLD
6	KSO5	O	OD	TRI	HOLD
7	KSO6	O	OD	TRI	HOLD
8	KSO7	O	OD	TRI	HOLD
9	KSO8	O	OD	TRI	HOLD
10	KSO9	O	OD	TRI	HOLD
11	KSO10	O	OD	TRI	HOLD
12	KSO11	O	OD	TRI	HOLD
13	V _{SS}				
14	V _{CC}				
15	KSO12	O	OD	TRI	HOLD
16	KSO13	O	OD	TRI	HOLD
17	KSO14	O	OD	TRI	HOLD
18	KSO15	O	OD	L	HOLD
19	KS10	I	5K–20K PU		NC
20	KS11	I	5K–20K PU		NC
21	KS12	I	5K–20K PU		NC
22	KS13	I	5K–20K PU		NC
23	KS14	I	5K–20K PU		NC
24	KS15	I	5K–20K PU		NC
25	KS16	I	5K–20K PU		NC
26	KS17	I	5K–20K PU		NC
27	ALE	O		L	L
28	MEMCSL	O		L (EAL = 0)	H
29	PSENL	O		L	L
30	P10/A0	I/O	PU	WH	HOLD
31	P11/A1	I/O	PU	WH	HOLD
32	P12/A2	I/O	PU	WH	HOLD
33	P13/A3	I/O	PU	WH	HOLD
34	P14/A4	I/O	PU	WH	HOLD
35	P15/A5	I/O	PU	WH	HOLD
36	P16/A6	I/O	PU	WH	HOLD
37	P17/A7	I/O	PU	WH	HOLD



8XC51SL/LOW VOLTAGE 8XC51SL PIN CHARACTERISTICS (Continued)

Table 2. Pin Characteristics (Continued)

Pin No.	Pin Name	Type	Term	Reset	PD Mode
38	V _{SS}				
39	V _{SS}				
40	ADB0	I/O		TRI	TRI
41	ADB1	I/O		TRI	TRI
42	ADB2	I/O		TRI	TRI
43	ADB3	I/O		TRI	TRI
44	ADB4	I/O		TRI	TRI
45	ADB5	I/O		TRI	TRI
46	ADB6	I/O		TRI	TRI
47	ADB7	I/O		TRI	TRI
48	P20/A8	I/O	PU	WH	HOLD
49	P21/A9	I/O	PU	WH	HOLD
50	P22/A10	I/O	PU	WH	HOLD
51	P23/A11	I/O	PU	WH	HOLD
52	P24/A12	I/O	PU	WH	HOLD
53	P25/A13	I/O	PU	WH	HOLD
54	P26/A14	I/O	PU	WH	HOLD
55	P27/LED4	I/O	OD	TRI	HOLD
56	V _{SS}				
57	GATEA20	O		WH	HOLD
58	PCDB7	I/O		TRI	TRI
59	PCDB6	I/O		TRI	TRI
60	PCDB5	I/O		TRI	TRI
61	PCDB4	I/O		TRI	TRI
62	PCDB3	I/O		TRI	TRI
63	PCDB2	I/O		TRI	TRI
64	RCL/PROGL	O		WH	HOLD
65	V _{CC}				
66	PCDB1	I/O		TRI	TRI
67	PCDB0	I/O		TRI	TRI
68	RST	I			
69	XTAL2	O			H
70	XTAL1	I			
71	PCOBF	O		L	HOLD
72	CSL	I			
73	RDL	I			
74	WRL	I			

8XC51SL/LOW VOLTAGE 8XC51SL PIN CHARACTERISTICS (Continued)

Table 2. Pin Characteristics (Continued)

Pin No.	Pin Name	Type	Term	Reset	PD Mode
75	A0	I			
76	AIN3	I			
77	AIN2	I			
78	AIN1	I			
79	AIN0	I			
80	AVREF				
81	AVGND				
82	V _{CC}				
83	V _{SS}				
84	P37/RDL	I/O	PU	WH	HOLD
85	P36/WRL	I/O	PU	WH	HOLD
86	P35/SIF11	I/O	OD	TRI	HOLD
87	P34/T0	I/O	PU	WH	HOLD
88	P33/SIF10	I/O	OD	L	HOLD
89	P32/INT0	I/O	PU	WH	HOLD
90	P31/SIF01	I/O	OD	TRI	HOLD
91	P30/SIF00	I/O	OD	L	HOLD
92	A1	I			
93	V _{SS}				
94	EAL	I			
95	LOADREN	I			
96	V _{SS}				
97	LED3	O	OD	TRI	HOLD
98	LED2	O	OD	TRI	HOLD
99	LED1	O	OD	TRI	HOLD
100	LED0	O	OD	TRI	HOLD

NOTES:

1. During Power Down mode all floating I/O pins or inputs without internal pullups should be driven.
2. PU = Pulled Up, OD = Open Drain, WH = Weak High, TRI = Tri-State.



PORT STRUCTURES AND OPERATION

All three 51SL ports are bidirectional. Each consists of a latch (Special Function Registers P1 through P3), an output driver, and an input buffer. Port 0 of the 51SL CPU does not connect to the package pins. It is used internally to drive the keyboard scan logic.

The output drivers of ports 1 and 2 can be used in accesses to external memory. The 51SL provides the LOADREN signal to facilitate external memory interfaces. When the LOADREN signal is high, Port 1 outputs the low byte of the external memory address. If LOADREN is tied low, then the Port 1 signals continue to emit the P1 SFR content. Port 2 outputs the upper seven bits of the high byte of the external address when the address is 15 bits wide and either EAL is tied low or EAL is tied high and Bit 0 (ADDREN) of configuration register 1 is set. Otherwise, the Port 2 pins continue to emit the P2 SFR content.

I/O Configurations

All port pins with the exception of P27/LED4, P30/SIF00, P31/SIF01, P33/SIF10, and P35/SIF11 have fixed internal pullups and therefore are called “quasi-bidirectional ports”. When configured as inputs, the pins are pulled high by the pullups and will source current when externally pulled low.

During a 15-bit external program memory access, Port 2 outputs the high address byte. In the 80C51 the Port 2 drivers use the strong pullup during the entire time that they are emitting a “1” on a Port 2 bit. In this instance, the 80C51 weak quasi-bidirectional pullup condition that normally occurs after two oscillator periods does not occur. Port 1 and Port 2 of the 51SL emulate the quasi-bidirectional pullup condition during program memory access, not this extended strong pullup condition.

POWER MANAGEMENT

The 51SL uses low power CHMOS and provides for two further power savings modes, available when inactive: Idle mode, typically between keystrokes; and Power Down mode, upon command from the host. A four channel, eight-bit A/D converter is also included for power management (i.e., battery voltage/temperature monitoring, etc.).

Idle Mode

Idle mode is initiated by an instruction that sets the PCON.0 bit (SFR address 87H) in the 51SL. In Idle mode, the internal clock signal to the 51SL CPU is gated off, but not to the interrupt timer and Serial Port functions. The 51SL status is preserved in its entirety: the Stack Pointer, Program Counter, Program Status Word, Accumulator, and all other registers maintain their data. The port pins hold the logic levels they had when Idle mode was activated. ALE and PSEN are held high. If an A/D conversion is in process when Idle mode is entered, any conversion results may contain erroneous data. Idle mode is exited via a hardware reset, or an enable interrupt.

Power Down Mode

Power Down mode is initiated by an instruction that sets bit PCON.1 in the 51SL CPU. When the 51SL enters Power Down mode, all internal clocks, including the 51SL core clock, are turned off. If an external crystal is used, the internal oscillator is turned off. MEMCSL, the external memory select signal, goes inactive unless it is configured as a general purpose I/O (i.e., unless bit 3 of configuration register 1 is a “1”). ALE and PSEN are both forced low. RAM contents are preserved.

Power Down mode can only be exited via a reset. This reset may occur either from the RST pin, or an internally generated reset. See the 51SL Hardware Description (Order No. #272268) for a detailed description of this reset.

HOST INTERFACE

The 51SL host interface is functionally compatible with the 8042 style UPI interface. It consists of the PCDB0–7 data bus; the RDL, WRL, A0 and CSL control signals; and the Keyboard Status register, Input Data register, and Output Data register. In addition, a second address line, A1, has been added to decode a second set of registers for power management functions. These registers are identical to the keyboard registers. The host interface also includes a PCOBF interrupt, GATEA20, and host reset (RCL) outputs. Two additional OBF signals, AUXOBF1 and AUXOBF2 are available through firmware configuration of P34/T0 and P37/RDL respectively.



KEYBOARD SCAN

The interface to the keyboard scan logic includes 16 slew-rate-controlled, open drain scan out lines (KSO0–15) and eight Schmitt trigger sense lines (KSI0–7) with internal pullup resistors. KSI0–7 connect directly to Port 0 of the 51SL CPU. The 16 scan out lines are controlled by the four low order bits of Port 0. Together KSO0–15 and KSI0–7 form a keyboard matrix.

EXTERNAL KEYBOARD AND MOUSE INTERFACE

Industry standard PC-AT compatible keyboards employ a two wire, bidirectional TTL interface for data transmission. Several sources also supply PS/2 mouse products that employ the same type of interface. To facilitate system expansion, the 51SL provides four signal pins that may be used to implement this interface directly for an external keyboard and mouse.

The 51SL has four high-drive, open-drain, bidirectional port pins that can be used for external serial interfaces, such as ISA external keyboard and PS/2-type mouse interfaces. They are P30/SIF00, P31/SIF01, P33/SIF10, and P35/SIF11. P33/SIF10 is connected to the firmware configurable level/edge sensitive INTL interrupt pin of the 51SL CPU. P30/SIF00 is connected to the edge sensitive SIF0INTL interrupt pin of the 51SL CPU. Note that on the Low Voltage 8XC51SL these inputs are protected to 5.5V in order to provide compatibility with as many external keyboard and PS/2 mouse devices as possible.

DESIGN CONSIDERATIONS

The low voltage characteristics of the Low Voltage 8XC51SL have indicated that additional care should be taken in selection of the crystal used in the oscillator circuit. In particular, series resistance of a crystal seems to have the largest effect on start-up time and steady state amplitude. Consequently, the lower the series resistance the better, although medium to better quality crystals are generally more than adequate.



ELECTRICAL SPECIFICATIONS

ABSOLUTE MAXIMUM RATINGS*

Ambient Temperature
 Under Bias -40°C to +85°C
 Storage Temperature -65°C to +150°C
 Voltage on Any Pin to V_{SS} ... -0.5V to V_{CC} + 0.5V
 Power Dissipation 1.0W**
 **This value is based on the maximum allowable die temperature and the thermal resistance of the package.

NOTICE: This data sheet contains information on products in the sampling and initial production phases of development. It is valid for the devices indicated in the revision history. The specifications are subject to change without notice.

**WARNING: Stressing the device beyond the "Absolute Maximum Ratings" may cause permanent damage. These are stress ratings only. Operation beyond the "Operating Conditions" is not recommended and extended exposure beyond the "Operating Conditions" may affect device reliability.*

OPERATING CONDITIONS

8XC51SL: T_A (Under Bias) = 0°C to +70°C, V_{CC} = +5V ± 10%, V_{SS} = 0V
 Low Voltage 8XC51SL: T_A (Under Bias) = 0°C to +70°C, V_{CC} = +3.3V ± 0.3V, V_{SS} = 0V

8XC51SL DC Characteristics (Over Operating Conditions)

Symbol	Parameter	Min	Max	Units	Test Conditions
V _{IL}	Input Low Voltage (Except XTAL1, RST)	-0.5	0.8	V	
V _{IL1}	Input Low Voltage (XTAL1, RST)	-0.5	0.2 V _{CC} - 0.1		
V _{IH}	Input High Voltage (Except EAL, PCDB0-7, ADB0-7, XTAL1, RST, CSL, RDL, WRL, LOADREN, A0, A1)	2.4	V _{CC} + 0.5	V	
V _{IH1}	Input High Voltage (EAL)	V _{CC} - 1.5	V _{CC} + 0.5	V	
V _{IH2}	Input High Voltage (PCDB0-7, ADB00-7, XTAL1, RST, CSL, RDL, WRL, LOADREN, A0, A1)	0.7 V _{CC}	V _{CC} + 0.5	V	
R _P	Internal Port Resistors KSI0-7	5	20	KΩ	
V _{OL}	Output Low Voltage BP Pins ⁽¹⁾ (Except P27/LED4)	-0.5	0.4	V	I _{OL} = 16 mA
V _{OL1}	Output Low Voltage P27/LED4, LED0-3	-0.5	0.8	V	I _{OL} = 12 mA
V _{OL2}	QB Pins ⁽²⁾ , PCDB0-7, RCL, ADB0-7, GATEA20, KSO0-15, MEMCSL, ALE, PSENL, PCOBF	-0.5	0.4	V	I _{OL} = 4 mA
V _{OH}	Output High Voltage QB Pins, ALE, PSENL, PCOBF	2.4	V _{CC} + 0.5	V	I _{OH} = -60 μA
V _{OH1}	Output High Voltage MEMCSL, PCDB0-7, ADB0-7	4.0	V _{CC} + 0.5	V	I _{OH} = -2.0 mA
V _{OH2}	Output High Voltage RCL, GATEA20	4.0	V _{CC} + 0.5	V	I _{OH} = 60 μA

ADVANCE INFORMATION

8XC51SL DC Characteristics (Over Operating Conditions) (Continued)

Symbol	Parameter	Min	Max	Units	Test Conditions
I_{IL}	Logical 0 Input Current QB(2) Pins		-50	μA	$V_{IN} = 0.4V$
I_{LI}	Input Leakage Current (BP and Pure Input Pins except for KSI0-7, XTAL1, and EAL)		± 10	μA	$0 < V_{IN} < V_{CC}$
I_{TL}	Logical 1 to 0 Transition Current QB(2) Pins		-1	mA	$V_{IN} = 2.0V$
I_{CC}	Power Supply Current Active Mode at 16 MHz Idle Mode at 16 MHz Power-Down Mode		38 15 TBD	mA mA μA	

Low Voltage 8XC51SL DC Characteristics (Over Operating Conditions)

Symbol	Parameter	Min	Max	Units	Test Conditions
V_{IL}	Input Low Voltage (Except XTAL1, RST, KSI0-7)	-0.5	0.8	V	
V_{IL1}	Input Low Voltage (XTAL1, RST)	-0.5	$0.2 V_{CC} - 0.1$		
V_{IL2}	Input Low Voltage (KSI0-7)	-0.5	0.6		
V_{IH}	Input High Voltage (Except EAL, PCDB0-7, ADB0-7, XTAL1, RST) P30, P31, P33, P35)	2.0	$V_{CC} + 0.5$	V	
V_{IH1}	Input High Voltage (EAL)	$V_{CC} - 1$	$V_{CC} + 0.5$	V	
V_{IH2}	Input High Voltage (PCDB0-7, ADB0-7, XTAL1, RST)	$0.7 V_{CC}$	$V_{CC} + 0.5$	V	
V_{IH3}	Input High Voltage (P30, P31, P33, P35)	2.0	5.5	V	
R_p	Internal Port Resistors KSI0-7	5	20	K Ω	
V_{OL}	Output Low Voltage BP Pins(1) (Except P27/LED4)	-0.5	0.4	V	$I_{OL} = 16 \text{ mA}$
V_{OL1}	Output Low Voltage P27/LED4, LED0-3	-0.5	0.8	V	$I_{OL} = 12 \text{ mA}$
V_{OL2}	Output Low Voltage QB Pins(2), PCDB0-7, RCL, ADB0-7, GATEA20, KSO0-15, MEMCSL, ALE, PSENL, PCOBF	-0.5	0.4	V	$I_{OL} = 4 \text{ mA}$
V_{OH}	Output High Voltage QB Pins, ALE, PSENL, PCOBF	$V_{CC} - 0.7$	$V_{CC} + 0.5$	V	$I_{OH} = -60 \mu A$
V_{OH1}	Output High Voltage MEMCSL, PCDB0-7, ADB0-7	2.4	$V_{CC} + 0.5$	V	$I_{OH} = -2.0 \text{ mA}$
V_{OH2}	Output High Voltage RCL, GATEA20	2.4	$V_{CC} + 0.5$	V	$I_{OH} = 60 \mu A$
I_{IL}	Logical 0 Input Current QB(2) Pins		-50	μA	$V_{IN} = 0.4V$
I_{LI}	Input Leakage Current (BP and Pure Input Pins except for KSI0-7, XTAL1, and EAL)		± 10	μA	$0 < V_{IN} < V_{CC}$

Low Voltage 8XC51SL DC Characteristics (Over Operating Conditions)

Symbol	Parameter	Min	Max	Units	Test Conditions
I_{TL}	Logical 1 to 0 Transition Current QB(2) Pins		-650	μA	$V_{IN} = 1.5V$
I_{CC}	Power Supply Current Active Mode at 16 MHz Idle Mode at 16 MHz Power-Down Mode		25 10 175	mA mA μA	

NOTES:

1. Bidirectional (BP) pins include P27/LED4, P30/SIF00, P31/SIF01, P33/SIF10, P36/SIF11, MEMCSL, PCDB0-7, and ADB0-7.
2. Quasi-bidirectional (QB) pins include P20-6/A8-A14, P32/INT0, P34/T0, P36/WRL, P37/RDL and P10-7/A0-7.
3. Pure input pins include LOADREN, EAL, A0, A1, CSL, RDL, WRL, RST, AIN0-3, and XTAL1.

AC Characteristics
Table 3. AC Symbol Characters
EXPLANATION OF THE AC SYMBOLS

Each timing symbol has three or five characters. The first character is always "T" (for time). The other characters, depending on their positions, stand for the name of a signal or the logical status of that signal. Table 3 lists the characters and their meanings.

Example

TAVLL = Time for Address Valid to ALE Low.
TLLPL = Time for ALE Low to PSEN Low.

Char.	Meaning
A	Address
C	Clock
D	Input Data
H	Logic Level HIGH
I	Instruction (Program Memory Contents)
L	Logic Level LOW, or ALE
P	PSENL
Q	Output Data
R	RDL Signal
T	Time
V	Valid
W	WRL Signal
X	No Longer a Valid Logic Level
Z	Float

HOST-INTERFACE TIMING

All Outputs Loaded with 50 pF

Symbol	Parameter	Min	Max	Units
TAR	CSL, A0/A1 Setup to RD Low	0		ns
TRA	CSL, A0/A1 Hold after RDL High	0		ns
TAD	CSL, A0/A1 to Data Out Delay		50	ns
TAW	CSL, A0/A1 Setup to WRL Low	0		ns
TWA	CSL, A0/A1 Hold after WRL High	10		ns
TDW	Data Setup to WRL High	60		ns
TWD	Data Hold after WRL High	5		ns
TWW	Minimum Pulse Width of WRL	50		ns
TRR	RDL Pulse Width	50		ns
TRD	RDL Low to Data Out Delay		50	ns
TDF	RDL High to Data Float Delay		50	ns

EXTERNAL MEMORY TIMING

TCLCL = 1 Clock Period, All Outputs Loaded with 50 pF

Symbol	Parameter	Min	Max	Units
1/TCLCL	Oscillator Frequency	2	16	MHz
TLHLL	ALE Pulse Width	2TCLCL – 40		ns
TAVLL	Address Valid to ALE Low	TCLCL – 40		ns
TLLAX	Address Hold after ALE Low	TCLCL – 30		ns
TLLIV	ALE Low to Valid Instruction In		4TCLCL – 100	ns
TLLPL	ALE Low to PSEN Low	TCLCL – 30		ns
TPLPH	PSEN Pulse Width	3TCLCL – 45		ns
TPLIV	PSEN Low to Valid Instruction In		3TCLCL – 105	ns
TPXIX	Input Instruction Hold after PSEN High	0		ns
TPXIZ	Input Instruction Float after PSEN High		TCLCL – 25	ns
TAVIV	Address to Valid Instruction In		5TCLCL – 105	ns
TPLAZ	PSEN Low to Address Float		10	ns
TRLRH	P37/RDL Pulse Width	6TCLCL – 50		ns
TWLWH	P36/WRL Pulse Width	6TCLCL – 50		ns
TRLDV	P37RDL Low to Valid Data In		5TCLCL – 100	ns
TRHDX	Data Hold after P37/RDL	0		ns
TRHDZ	Data Float after P37/RDL		2TCLCL – 50	ns
TLLDV	ALE Low to Valid Data In		8TCLCL – 100	ns
TAVDV	Address to Valid Data In		9TCLCL – 100	ns
TLLWL	ALE Low to P37/RDL or P36/WRL Low	3TCLCL – 25	3TCLCL + 25	ns
TAVWL	Address Valid to P36/WRL Low	4TCLCL – 50		ns
TQVWX	Data Valid before P36/WRL	TCLCL – 25		ns
TWHQX	Data Hold after P36/WRL	TCLCL – 25		ns
TQVWH	Data Valid to P36/WRL High	7TCLCL – 50		ns
TRLAZ	P37/RDL Low to Address Float		0	ns
TWHLH	P37/RDL or P36/WRL High to ALE High	TCLCL – 25	TCLCL + 25	ns

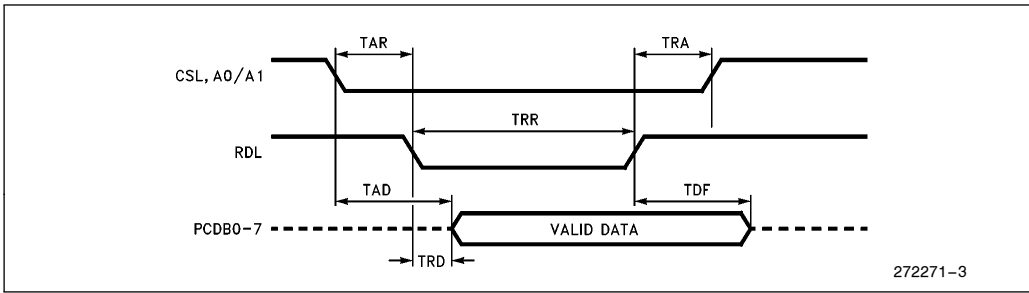


Figure 3. Host-Interface Read

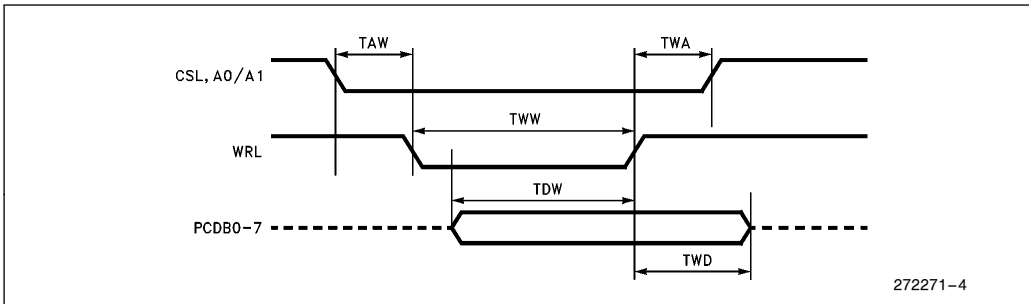


Figure 4. Host-Interface Write

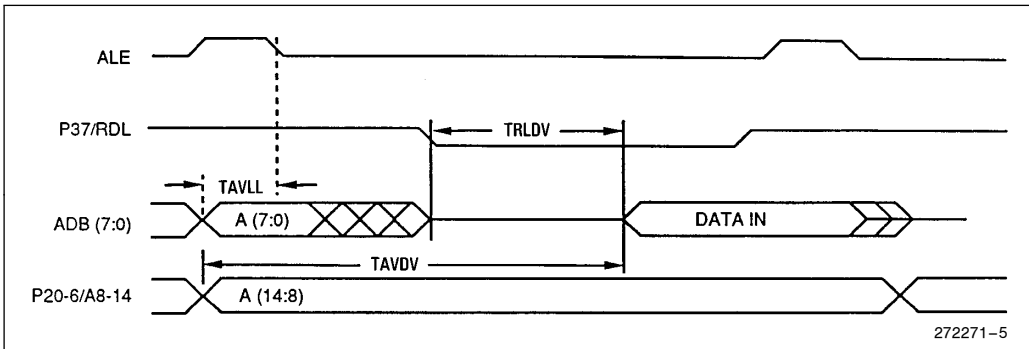


Figure 5. External Data Memory Read

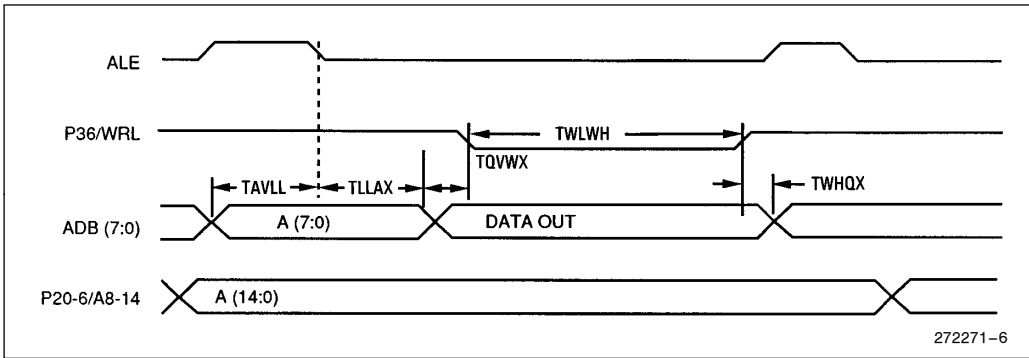


Figure 6. External Data Memory Write

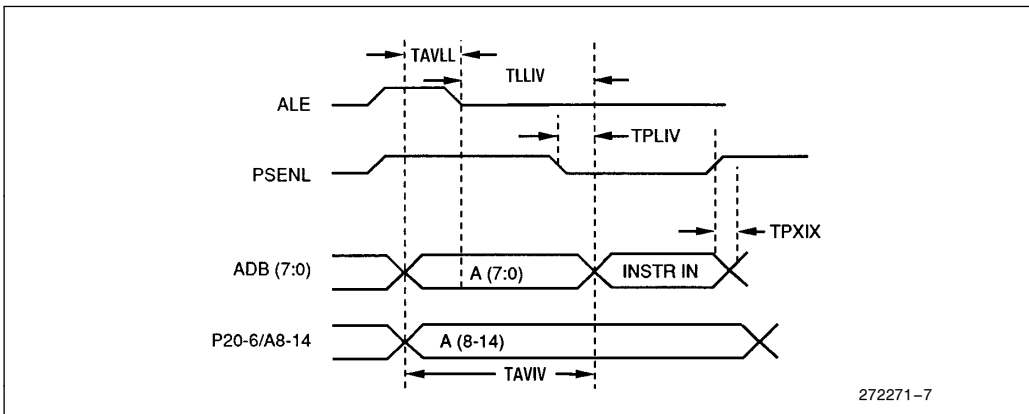


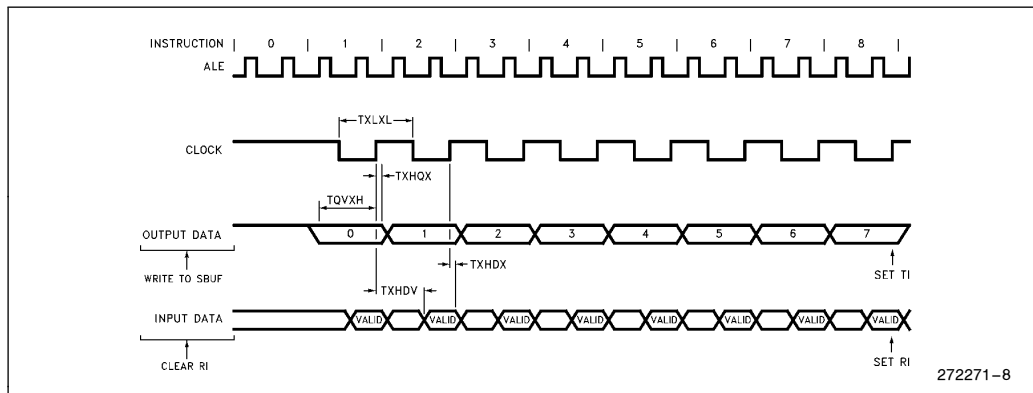
Figure 7. External Program Memory Read

SERIAL PORT TIMING—SHIFT REGISTER MODE

Test Conditions: Over Operating Conditions, Load Capacitance = 50 pF

Symbol	Parameter	16 MHz Oscillator		Variable Oscillator		Units
		Min	Max	Min	Max	
TXLXL	Serial Port Clock Cycle Time	750		12TCLCL		ns
TQVXH	Output Data Setup to Clock Rising Edge	492		10TCLCL – 133		ns
TXHQX	Output Data Hold after Clock Rising Edge	50		2TCLCL – 117		ns
TXHDX	Input Data Hold after Clock Rising Edge	0		0		ns
TXHDV	Clock Rising Edge to Input Data Valid		492		10TCLCL – 133	ns

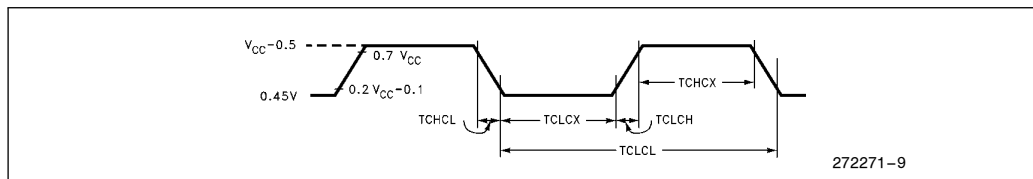
SHIFT REGISTER MODE TIMING WAVEFORMS



EXTERNAL CLOCK DRIVE

Symbol	Parameter	Min	Max	Units
1/TCLCL	Oscillator Frequency	2.0	16	MHz
TCHCX	High Time	20		ns
TCLCX	Low Time	20		ns
TCLCH	Rise Time		20	ns
TCHCL	Fall Time		20	ns

EXTERNAL CLOCK DRIVE WAVEFORM



PROGRAMMING THE OTP

The part must be running with a 4 MHz to 6 MHz oscillator. The address of a location to be programmed is applied to address lines, while the code byte to be programmed in that location is applied to data lines. Control and program signals must be held at the levels indicated in Table 4. Normally EAL/V_{PP} is held at a logic high until just before RCL/PROGL is to be pulsed. The EAL/V_{PP} is raised to V_{PP}, RCL/PROGL is pulsed low and then EAL/V_{PP} is returned to V_{CC} (also refer to timing diagrams). Also, the LOADREN signal must be grounded when programming or verifying.

NOTE:

Exceeding the V_{PP} maximum for any amount of time could damage the device permanently. The V_{PP} source must be well regulated and free of glitches.

DEFINITION OF TERMS

ADDRESS LINES: P10–P17, P20–P25, respectively for A0–A13.

DATA LINES: ADB0–7.

CONTROL SIGNALS: RST, GATEA20, P26, P27, P32, P36, P37.

PROGRAM SIGNALS: RCL/PROGL, EAL/V_{PP}.


PROGRAMMING ALGORITHM

Refer to Table 4 and Figures 8 and 9 for address, data and control signals setup. To program the 87C51SL the following sequence must be exercised.

1. Input the valid address on the address lines.
2. Input the appropriate data byte on the data lines.
3. Activate the correct combination of control signals.
4. Raise EAL/V_{PP} from V_{CC} to 12.75V ±0.25V.
5. Pulse RCL/PROGL 5 times.

Repeat 1 through 5 changing the address and data for the entire array or until the end of the object file is reached.

Table 4. OTP Programming Modes

Mode	RST	GATEA20	RCL/ PROGL	EAL/V _{PP}	P26	P27	P32	P36	P37
Program Code Data	H	L		12.75V	L	H	H	H	H
Verify Code Data	H	L	H	H	L	L	L	H	H
Read Signature Byte	H	L	H	H	L	L	L	L	L

Note that in the above table, to program code data on the Low Voltage 87C51SL V_{CC} must be raised to 5V ±10%. In addition, all address lines, data lines, and control signals being driven to a “High” level must be raised to 5V ±10%. The RCL/PROGL signal must pulse between 0V and 5V ±10%.

To verify code data or read the signature bytes of the Low Voltage 87C51SL V_{CC} must be set to 3.3V

±0.3V. In addition, all address lines and control signals being driven to a “High” level must be raised to 3.3V ±0.3V.

For the standard (5V version) of the 87C51SL V_{CC} must always be at 5V ±10%, and all “High” voltages must meet the DC specs indicated in the DC Characteristics section of this document.

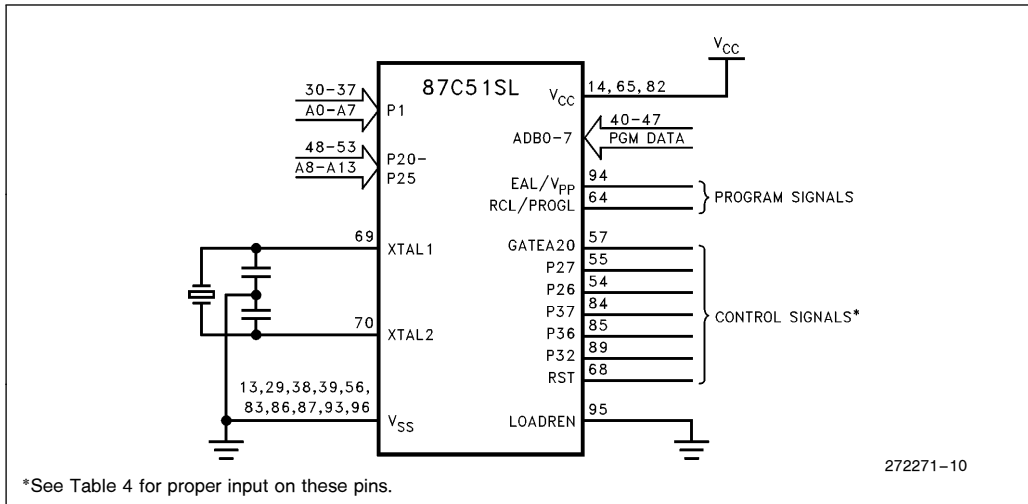


Figure 8. Programming/Verifying the OTP

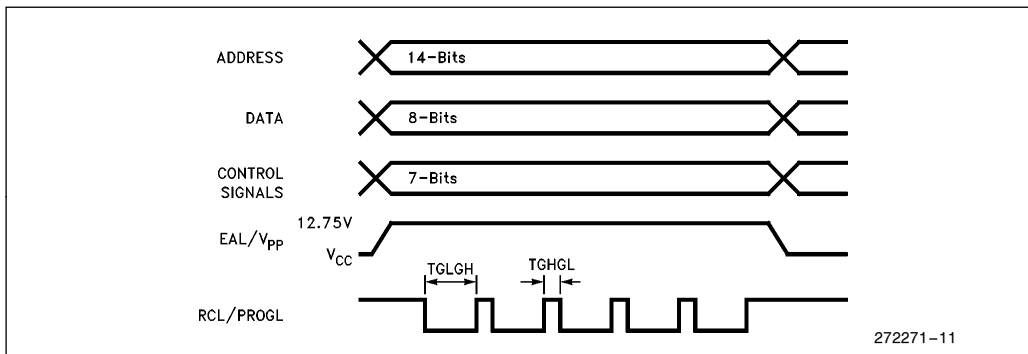


Figure 9. Programming Signal's Waveforms

PROGRAM VERIFY

Program verify may be done after each byte that is programmed, or after a block of bytes that is programmed. In either case a complete verify of the array will ensure that it has been programmed correctly.

READING THE SIGNATURE BYTES

The 8XC51SL and Low Voltage 8XC51SL each have three signature bytes in locations 30H, 31H, and 60H. To read these bytes, follow the procedure for EPROM verify, but activate the control lines provided in Table 4 for Read Signature Byte.

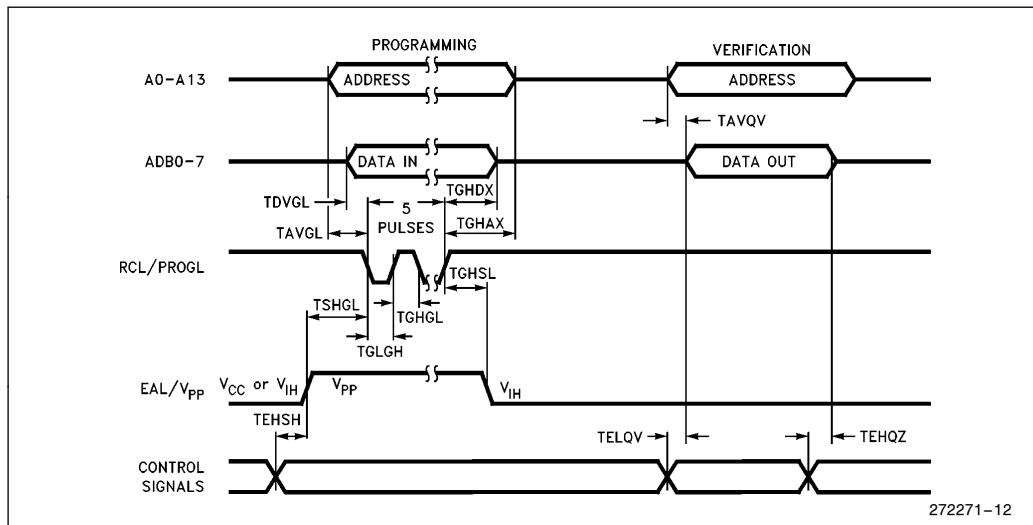
Location	Contents			
	87C51SL	83C51SL	Low Voltage 87C51SL	Low Voltage 83C51SL
30H	89H	89H	89H	89H
31H	58H	58H	58H	58H
60H	BBH	3BH	ABH	2BH

OTP PROGRAMMING AND VERIFICATION CHARACTERISTICS

$T_A = 21^{\circ}\text{C}$ to 27°C ; $V_{CC} = 5\text{V} \pm 10\%$ for 87C51SL, $3.3\text{V} \pm 0.3\text{V}$ for Low Voltage 87C51SL (verification only). V_{CC} for programming the Low Voltage 87C51SL must be $5.0\text{V} \pm 10\%$. $V_{SS} = 0\text{V}$

Symbol	Parameter	Min	Max	Units
V_{PP}	Programming Supply Voltage	12.5	13.0	V
I_{PP}	Programming Supply Current		75	mA
$1/TCLCL$	Oscillator Frequency	4	6	MHz
TAVGL	Address Setup to PROGL Low	48TCLCL		
TGHAX	Address Hold after PROGL	48TCLCL		
TDVGL	Data Setup to PROGL Low	48TCLCL		
TGHDX	Data Hold after PROGL	48TCLCL		
TEHSH	(Enable) High to V_{PP}	48TCLCL		
TSHGL	V_{PP} Setup to PROGL Low	10		μs
TGHSL	V_{PP} Hold after PROGL	10		μs
TGLGH	PROGL Width	90	110	μs
TAVQV	Address to Data Valid		48TCLCL	
TELQV	ENABLE Low to Data Valid		48TCLCL	
TEHQZ	Data Float after Enable	0	48TCLCL	
TGHGL	PROGL High to PROGL Low	10		μs

PROGRAMMING AND VERIFICATION WAVEFORMS





A/D CHARACTERISTICS

The 51SL includes a four-channel, 8-bit A/D converter. This A/D, with eight bits of accuracy, uses successive approximation with a switch capacitor comparator. It is designed to be used for sampling static analog signals (i.e., ideally suited for power management tasks such as battery voltage monitoring, etc.). The nominal conversion rate is 20 μ s at 16 MHz. The analog high and low voltage references are connected to AVREF and AVGND, respectively. The four input channels, AIN0–3 are connected from the package pins, unbuffered, to an analog multiplexer (on-chip). The absolute conversion accuracy is dependent upon the accuracy of AVREF. The specifications given assume adherence to the operating conditions section of this data sheet.

Testing is done at AVREF = 5.12V and V_{CC} = 5.0V for the 8XC51SL, and at AVREF = 3.2V and V_{CC} = 3.3V for the Low Voltage 8XC51SL.

OPERATING CONDITIONS

V _{CC}	8XC51SL	4.5V to 5.5V
	Low Voltage 8XC51SL	3.0V to 3.6V
AVREF	8XC51SL	4.5V to 5.5V
	Low Voltage 8XC51SL	3.0V to 3.6V
V _{SS} , AVSS		0V
AIN0–3		AVSS to AVREF
T _A		0°C to +70°C Ambient
F _{OSC}		2 MHz to 16 MHz

A/D CONVERTER SPECIFICATIONS (Over Operating Conditions)

Parameter	Min	Typ	Max	Units
Resolution	255		256	Levels
	8		8	Bits
Absolute Error	0		± 1	LSB
Full Scale Error		± 1		LSB
Zero Offset Error		± 1		LSB
Non-Linearity Error	0		± 1	LSB
Differential Non-Linearity Error	0		± 1	LSB
Channel to Channel Matching	0		± 1	LSB
Repeatability		± 0.25		LSB
Temperature Coefficients				
Offset		0.003		LSB/°C
Full Scale		0.003		LSB/°C
Differential Non-Linearity		0.003		LSB/°C
Off Isolation	– 60			dB
Feedthrough		– 60		dB
V _{CC} Power Supply Rejection		– 60		dB
Input Resistance	750		1.2K	Ω
Input Capacitance		3		pF
DC Input Leakage	0		3.0	μ A

A/D Glossary of Terms

Absolute Error—The maximum difference between corresponding actual and ideal code transitions. Absolute Error accounts for all deviations of an actual converter from an ideal converter.

Actual Characteristic—The characteristic of an actual converter. The characteristic of a given converter may vary over temperature, supply voltage, and frequency conditions. An actual characteristic rarely has ideal first and last transition locations or ideal code widths. It may even vary over multiple conversions under the same conditions.

Break-Before-Make—The property of a multiplexer which guarantees that a previously selected channel will be deselected before a new channel is selected (e.g., the converter will not short inputs together).

Channel-to-Channel Matching—The difference between corresponding code transitions of actual characteristics taken from different channels under the same temperature, voltage and frequency conditions.

Characteristic—A graph of input voltage versus the resultant output code for an A/D converter. It describes the transfer function of the A/D converter.

Code—The digital value output by the converter.

Code Center—The voltage corresponding to the midpoint between two adjacent code transitions.

Code Transition—The point at which the converter changes from an output code of Q , to a code of $Q + 1$. The input voltage corresponding to a code transition is defined to be that voltage which is equally likely to produce either of two adjacent codes.

Code Width—The voltage corresponding to the difference between two adjacent code transitions.

Crosstalk—See “Off-Isolation”.

DC Input Leakage—Leakage current to ground from an analog input pin.

Differential Non-Linearity—The difference between the ideal and actual code widths of the terminal based characteristic.

Feedthrough—Attenuation of a voltage applied on the selected channel of the A/D Converter after the sample window closes.

Full Scale Error—The difference between the expected and actual input voltage corresponding to the full scale code transition.

Ideal Characteristic—A characteristic with its first code transition at $V_{IN} = 0.5 \text{ LSB}$, its last code transition at $V_{IN} = (V_{REF} - 1.5 \text{ LSB})$ and all code widths equal to one LSB.

Input Resistance—The effective series resistance from the analog input pin to the sample capacitor.

LSB—Least Significant Bit—The voltage corresponding to the full scale voltage divided by 2^n , where n is the number of bits of resolution of the converter. For an 8-bit converter with a reference voltage of 5.12V, one LSB is 20 mV. Note that this is different than digital LSBs since an uncertainty of two LSBs, when referring to an A/D converter, equals 40 mV. (This has been confused with an uncertainty of two digital bits, which would mean four counts, or 80 mV).

Monotonic—The property of successive approximation converters which guarantees that increasing input voltages produce adjacent codes of increasing value, and that decreasing input voltages produce adjacent codes of decreasing value.

No Missed Codes—For each and every output code, there exists a unique input voltage range which produces that code only.

Non-Linearity—The maximum deviation of code transitions of the terminal based characteristic from the corresponding code transitions of the ideal characteristic.

Off-Isolation—Attenuation of a voltage applied on a deselected channel of the A/D converter. (Also referred to as Crosstalk.)

Repeatability—The difference between corresponding code transitions from different actual characteristics taken from the same converter on the same channel at the same temperature, voltage and frequency conditions.

Resolution—The number of input voltage levels that the converter can unambiguously distinguish between. Also defines the number of useful bits of information which the converter can return.

Sample Delay—The delay from receiving the start conversion signal to when the sample window opens.

Sample Delay Uncertainty—The variation in the sample delay.

Sample Time—The time that the sample window is open.

Sample Time Uncertainty—The variation in the sample time.



Sample Window—Begins when the sample capacitor is attached to a selected channel and ends when the sample capacitor is disconnected from the selected channel.

Successive Approximation—An A/D conversion method which uses a binary search to arrive at the best digital representation of an analog input.

Temperature Coefficients—Change in the stated variable per degree centigrade temperature change. Temperature coefficients are added to the typical values of a specification to see the effect of temperature drift.

Terminal Based Characteristic—An actual characteristic which has been rotated and translated to remove zero offset and full scale error.

V_{CC} Rejection—Attenuation of noise on the V_{CC} line to the A/D converter.

Zero Offset—The difference between the expected and actual input voltage corresponding to the first code transition.

DATA SHEET REVISION SUMMARY

The following differences exist between this data sheet (272271-002) and the previous version (272271-001).

1. Data sheet status changed from “Product Preview” to “Advance Information”.
2. Title page item number three describing the global interrupt enable change was removed.
3. Title page item number two was corrected to read “. . . was added in configuration register 1.”
4. In the 8XC51SL DC Characteristics section:
 - The V_{OH} test condition (I_{OH}) changed from -0.8 mA to -60 μA.
 - The V_{OH1} test condition (I_{OH}) changed from -4.0 mA to -2.0 mA.
 - V_{OH2} was added.
 - The XTAL1 and EAL pins were added to the I_{L1} spec.

The I_{TL} spec changed from -650 μA to -1 mA.
 The I_{CC} idle spec changed from 10 mA to 15 mA.
 The I_{CC} Power Down spec changed from 100 μA to TBD.

5. In the Low Voltage 8XC51SL DC Characteristics section:
 - The V_{OH} spec changed from 2.4V to V_{CC} - 0.7
 - The V_{OH} test condition (I_{OH}) changed from -0.8 mA to -60 μA.
 - V_{OH2} was added.
 - Pins were clarified in the I_{L1} spec.
 - The I_{TL} test condition (V_{IN}) was changed from TBD to 1.5V.
 - The I_{CC} Power Down spec changed from 100 μA to 175 μA.
6. The load capacitance for all timing tables was changed to 50 pF.
7. In the Host Interface Timing Section TWD changed from 0 ns to 5 ns.
8. The External Memory Timing table changed as follows:

Spec.	Old	New
TLLIV	4TCLCL-50	4TCLCL-100
TPLIV	3TCLCL-50	3TCLCL-105
TPXIZ	TCLCL-15	TCLCL-25
TAVIV	5TCLCL-50	5TCLCL-105
TRLDV	5TCLCL-50	5TCLCL-100
TLLDV	8TCLCL-50	8TCLCL-100
TAVDV	9TCLCL-50	9TCLCL-100
TMVDV	9TCLCL-50	Removed
TMVIV	5TCLCL-50	Removed

9. In Figures 5 and 7 the MEMCSL waveforms were removed.
10. Clarification was added in the Programming Algorithm section.
11. In the A/D Converter Specifications section the minimum resolution was changed from 256 levels to 255 levels.
12. The Data Sheet Revision Summary was added.